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Testing Phase Noise of Ultra Low Phase Noise OCXOs

Challenges and Solutions

Roman Boroditsky
Jorge Gomez
NEL Frequency Controls

AUGUST 2023

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Abstract

Modern instrumentation equipment, commercial & defense communication systems, and radar equipment require excellent stability and extremely low phase noise frequency sources. Testing devices that exhibit phase noise of -120 dBc/Hz at 1 Hz offset from the carrier and better than -180 dBc/Hz on the noise floor is a challenge using existing test equipment and methods. It is especially pertinent to production environment, where measurement time and accuracy of each measurement becomes critical. The purpose of this work was to investigate different test methods, evaluate various phase noise measurement equipment, and find acceptable solutions for both low frequency (around 10 MHz) Ultra Low Phase Noise (ULPN) reference, and HF/UHF ULPN OCXO. Several test methods and test instruments were investigated. There's no "one size fits all" solution, but for each frequency range the optimum solutions were proposed.

Introduction and Challenges

There are several criteria that define acceptability of the test methods and equipment used in the measurements of phase noise of ultra low noise (ULPN) OCXO. These are:

1. Accuracy
2. Repeatability
3. Speed of test
4. Ease of use
5. Range
6. Cost
7. Ease of data retrieval

The value of each characteristic also depends on whether the test is intended for use in production environment, or in the lab. The “two oscillator method” [1] was ruled out, since it does not satisfy the first four criteria very well, and therefore only methods and equipment, employing cross-correlation technique were considered. [1], [4]. The challenges for lower frequency devices (around 10.000 MHz) were:

- a) Achieving measurement accuracy in a reasonable amount of time at offset points close to the carrier. Reaching the noise floor farther away from the carrier. For higher frequency ULPN OCXO, specifically at 100.000 MHz carrier frequency, RF pollution in the environment, and EMI added further challenges.
- b) For devices, which employ a phase lock loop (PLL) technique for attaining higher frequency the interaction of the device PLL and test instrument’s PLLs made it increasingly difficult to achieve accurate results.

I. Low Frequency ULPN OCXO

The obvious choice of equipment for testing low frequency OCXOs was Symmetricomm's 5120A Phase Noise Test Set with option 01 (internal reference) [3], which uses cross-correlation technique. It satisfies the majority of the established criteria, and does not require additional references, nor calibration of the device under test (DUT) on exact frequency. The phase noise plot of 10.000 MHz ULPN OCXO is shown on Fig.1.

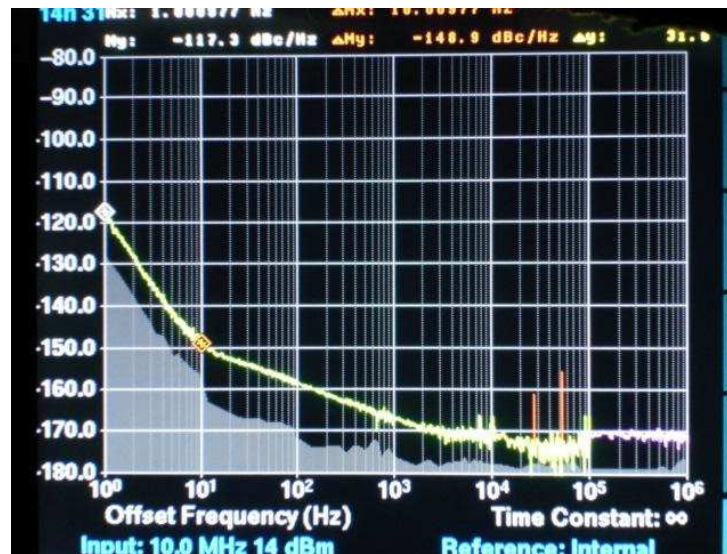


Fig.1. 10 MHz ULPN OCXO on 5120A – 01

The primary concern was the resolution (noise floor) of the measurement at large offsets from the carrier (the noise floor of the device). The instrument's specification calls (conservatively) for -168 dBc/Hz floor at offsets greater than 10 KHz. The theoretical expectations were closer to -175 dBc/Hz at 100 KHz offsets and beyond. It was decided to verify these expectations with a Noise XT Dual Core Noise Test Set (DCNTS) [2], [4]. However, it is a considerably more difficult type of test. It requires two references with similar performance as the DUT (the better the references' performance – the faster the test), the references must have voltage control (ability to change frequency with the change of the voltage on the control terminal), and be calibrated exactly on the frequency of DUT. The test result of the same device is shown in Fig.2.

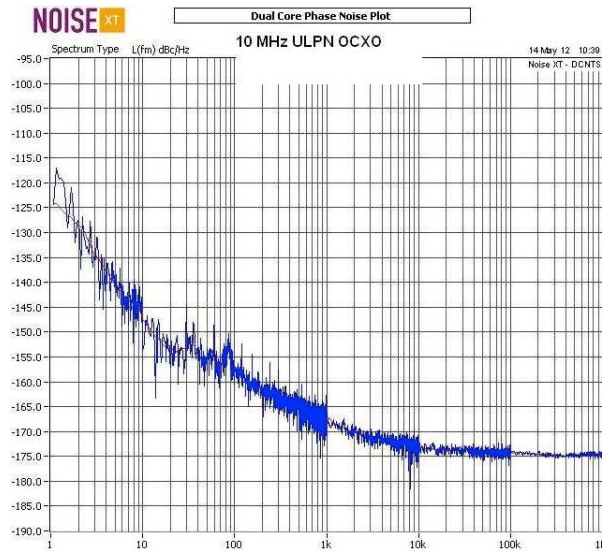


Fig.2. 10.000 MHz ULPN OCXO on DCNTS

As expected, the measured phase noise far from the carrier was improved by 3dB to 5dB, while discrepancies in results from a few KHz offset were not very noticeable. Realizing that the phase noise on the noise floor is determined by the circuit, and for a given design; unit to unit variations are negligible, the instrument of choice would still be 5120A-01. However, during the design qualification stage, the verification of the noise floor values on the DCNTS is required.

II. 100.000 MHZ ULPN OCXO

There's no ideal option to satisfy all established criteria. We started with presumably the most accurate and fastest instrument – the DCNTS from Noise XT. The first results were surprising and the plot is shown in Fig. 3.

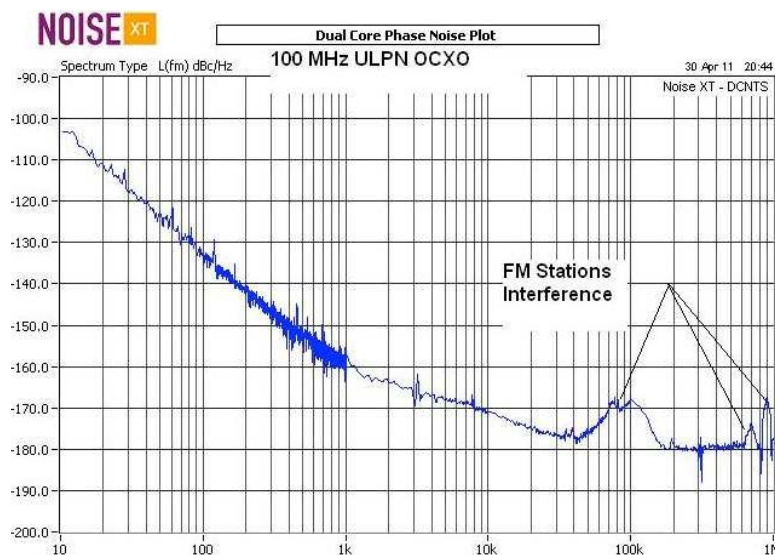


Fig. 3. 100 MHz ULPN OCXO with “bumps” caused by RF pollution.

After a lengthy and thorough investigation, it turned out that the spurious “bumps” at 100 KHz, 700 KHz, and 900 KHz offsets from the carrier were caused by mixing the broadcast signals from the local FM radio stations (at 100.1 MHz, 100.7 MHz, 99.1 MHz) with 100 MHz OCXO signal. While testing good, but not ULPN 100 MHz devices, (which have noise floor at -170 dBc/Hz or higher), this phenomenon is hardly noticeable. Therefore, it was deduced that this challenge is specific to ULPN OCXO with a phase noise floor around -180 dBc/Hz, particularly running at 100 MHz, especially in urban areas, where the power from the FM stations is quite high. If the frequency is far away from the broadcasting FM band, this phenomenon doesn't occur. In order to rectify this challenge, several measures were undertaken:

- All power supply cables were shielded and connected to the test fixtures via SMA connectors.
- Large value electrolytic capacitors were placed for decoupling power supply cords
- A RF shielding cage was built and all test equipment was situated within, including power supplies and test fixtures as shown in Fig. 4.



Fig. 4. RF shielded test station.

The resulting phase noise with the improved setup is shown in Fig 5. Also included is the plot with data taken on a batch of ULPN OCXOs in a benign (RF pollution-wise) environment, courtesy of Guillaume De Giovanni, Noise XT. The test instrument is the same DCNTS with the “smooth” function used, as shown in Fig. 6.

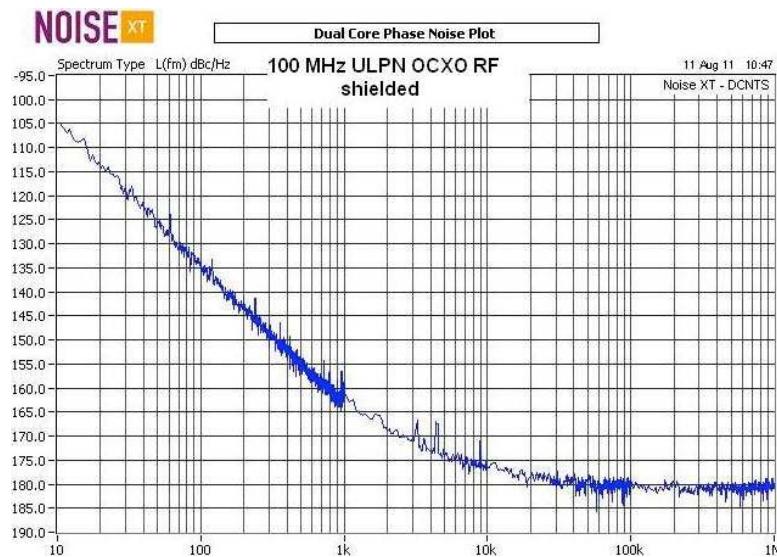


Fig. 5. 100.000 MHz ULPN OCXO phase noise tested with RF-shielded setup.

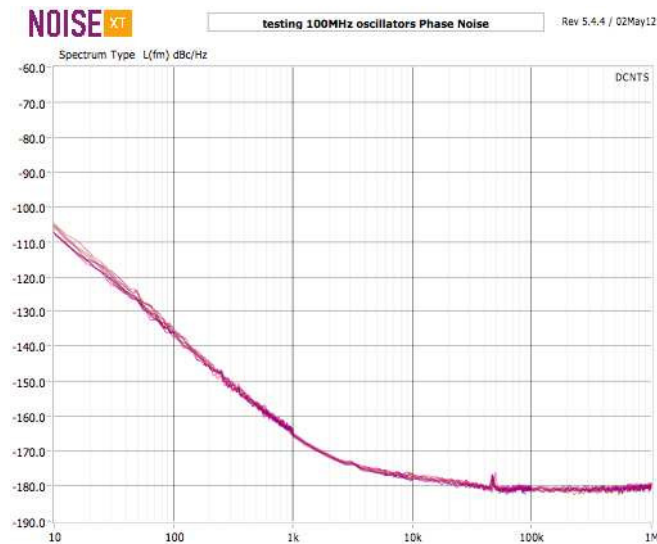


Fig. 6. A batch of 100.000 MHZ ULPN OCXO tests in benign environment. Smooth function is used.

From the ease of use standpoint, a very attractive option is Agilent's E5052B Signal Source Analyzer [5]. Additional testing was performed on the device, similar in performance to the one shown in Fig. 5. using the E5052B. The instrument utilizes built-in synthesizers and the cross-correlation method.

The plot of the experiment with varying numbers of cross correlations and averages is shown in Fig. 7. As shown in the plot, the instrument can resolve the performance of a ULPN device with sufficient number of cross-correlations, but unfortunately, it takes an enormous amount of time to do so. One would have to run the test for several hours to get the noise floor of the instrument at all offset points - low enough to achieve an accurate measurement. This would rule out the use of this instrument in production environment, but it still is useful in R&D, since it doesn't require additional references or calibration of the references and devices (setting on exact frequency), etc. Further, if the performance on the noise floor of the device far from the carrier frequency is the only parameter needed, the measurement time can be significantly reduced.

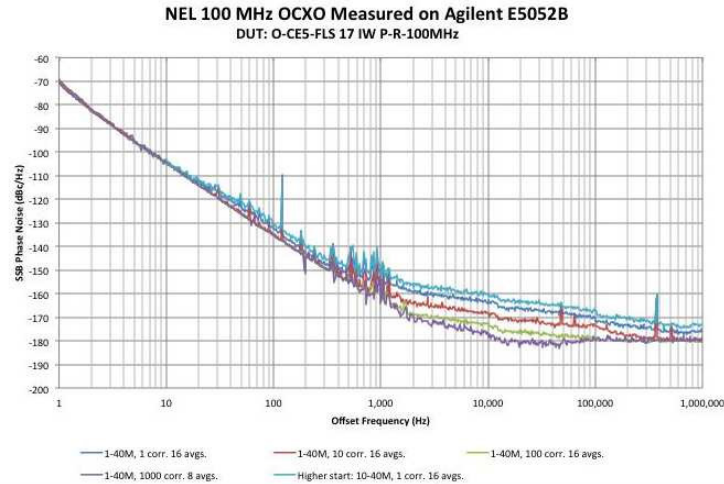


Fig. 7. 100 MHz ULPN OCXO tested on Agilent E5052B with different number of cross-correlations and averages.

From a cost standpoint, there's one new instrument made by the Swiss company Anapico APPH6000 [6]. It doesn't have as many options and capabilities as the DCNTS system, and is still in the process of improving GUI and firmware, but it tests reasonably fast and can be used successfully in a production environment. However, test results are not as presentable as with other instruments. Example is shown on Fig. 8.

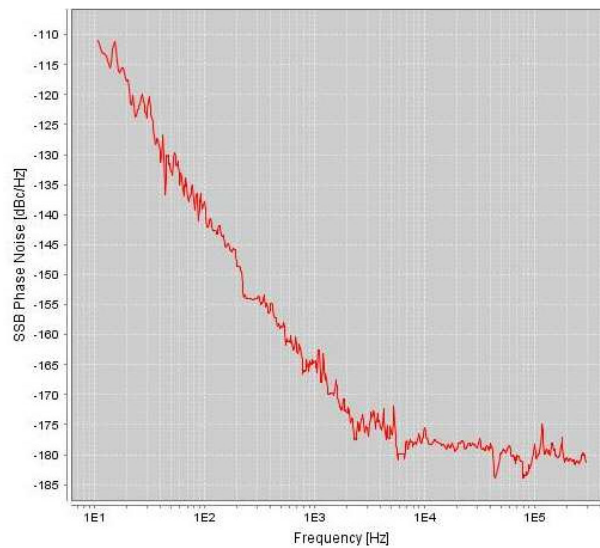


Fig. 8. 100 MHz ULPN OCXO tested on Anapico APPH6000

III. ULPN OCXO With Multiplication

A. Analog harmonic multiplication

We tested several ULPN OCXOs, which employed analog harmonic multiplication, with references ranging from 10 MHz to 100 MHz and multiplication factors from 2 to 15 on the DCNTS from Noise XT. The instrument handled tests without problems and some of the examples are shown on Fig. 9. through Fig. 12.

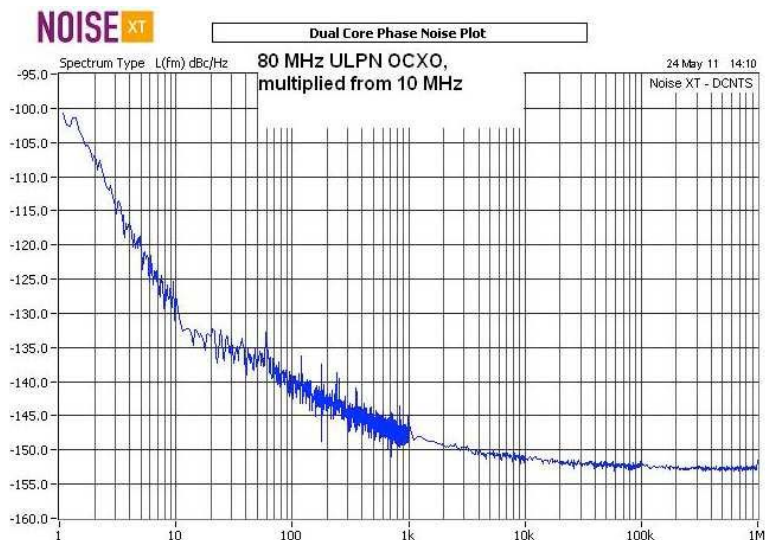


Fig. 9. 80 MHz ULPN OCXO, multiplied from 10 MHz

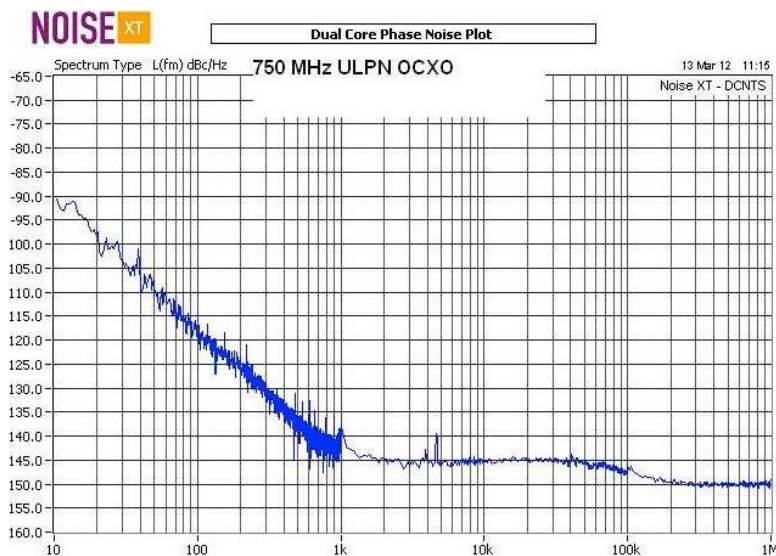


Fig. 10. 750 MHz ULPN OCXO, multiplied from 50 MHz

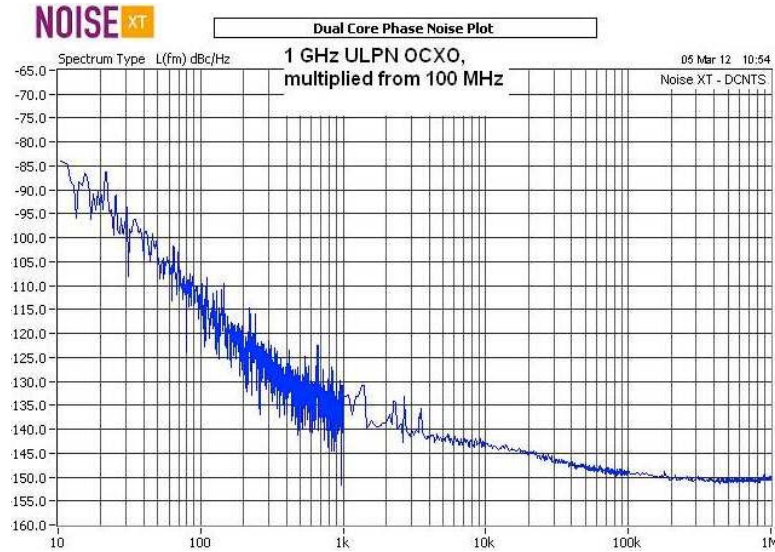


Fig. 11. 1 GHz ULPN OCXO, multiplied from 100 MHz

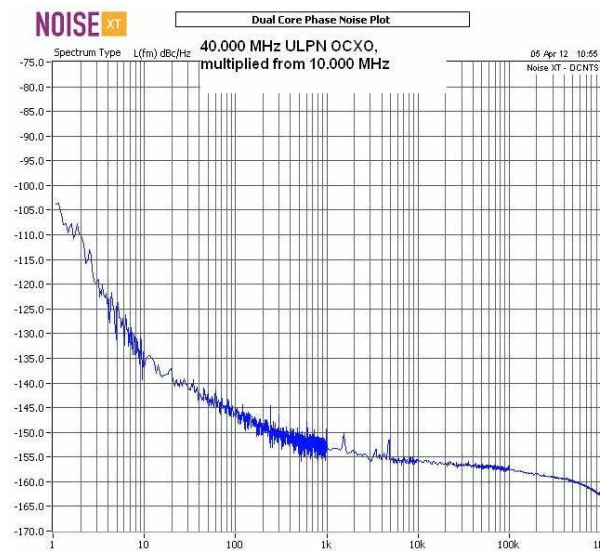


Fig. 12. 40 MHz OCXO, multiplied from 10 MHz

Additional tests were conducted on one of those units (100.000 MHz, multiplied from 10.000 MHz) on the E5052B with different number of cross-correlations and averages. The plot is shown in Fig. 13. Similar to testing the ULPN devices with no multiplication, despite the ease of use, the speed of test required to achieve meaningful resolution is not acceptable in a production environment. With 1,000 cross correlations it took over 2.5 hours for the first trace (1 average) to appear.

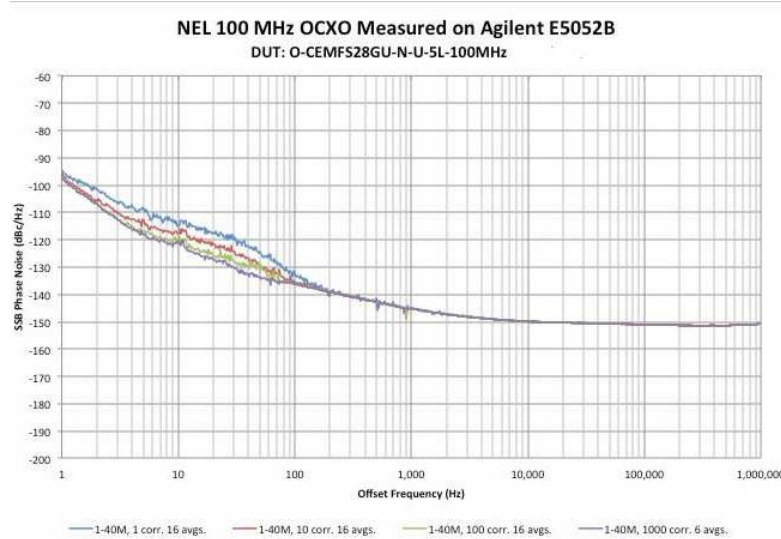


Fig. 13. 100 MHz ULPN OCXO multiplied from 10 MHz, tested on Agilent E5052B with various number of crosscorrelations and averages

B. ULPN OCXO with PLL multiplication

To achieve “the best of both worlds” i.e. combine the best close to the carrier phase noise, short term, long term, and environmental stability of the low frequency (10 MHz) ULPN OCXO with the lowest phase noise on the noise floor of high frequency (100 MHz) ULPN OCXO, the latter is locked to the former to a low noise PLL, as it is done in NEL’s dual frequency reference module (DFRM). Testing of the 10 MHz output can be done as described in chapter I, without presenting any additional challenges.

It is increasingly difficult to achieve realistic test results for the 100 MHz output while testing with two other DFRMs as references. The interaction of internal PLLs with instrument’s PLLs along with the necessary filtering on control ports of the modules creates artifacts in the phase noise plot, making the data mostly unusable. The only viable path is to make the test run for different offset ranges, using different references, and concatenate them afterwards. The result of this effort is shown on Fig.14. For higher frequency offsets non-multiplied ULPN OCXOs at 100 MHz were used as references. These were free running with voltage control used by the instrument’s PLL. For lower frequency offsets, a ULPN OCXO at 100 MHz was used, which was harmonically multiplied from a 10 MHz reference. The splicing point is at 100 Hz, just below the internal PLL loop bandwidth.

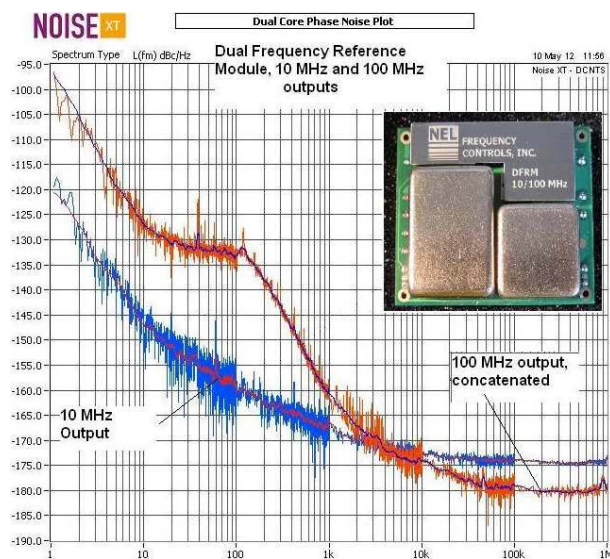
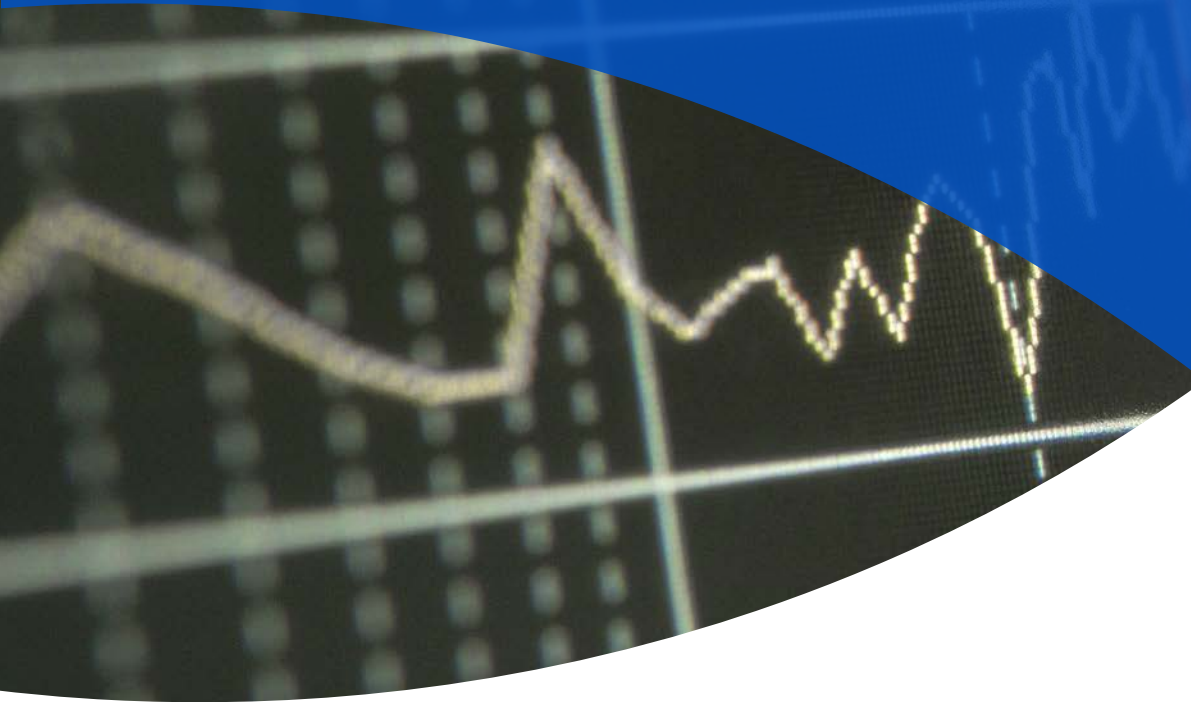


Fig. 14. DFRM phase noise. Outputs at 10 MHz and 100 MHz



IV. Conclusions

Testing phase noise of ULPN OCXOs requires using the cross-correlation technique. Special care must be taken for reduction of RF interference, especially while testing 100 MHz ULPN OCXO in the vicinity of strong FM broadcasting stations. The choices of readily available equipment are limited, and the instruments are suited differently to different types of DUTs and different purposes of test. Our rating of evaluated instruments is presented in Table I. We want to emphasize that this is applicable for ULPN devices only. We had very little experience with the Rohde & Schwartz signal analyzer, but expect that it would rate similarly to E5052.

Category	Test Instrument for testing phase noise ULPN OCXO			
	<i>DCNTS</i>	<i>E5052B</i>	<i>5120A-01</i>	<i>APPH6000</i>
Accuracy	★★★★★	★★★★ (note1)	★★★★ (note2)	★★★★
Speed	★★★★★	★ (note3)	★★★★	★★★★★
Ease of use	★★	★★★★	★★★★★	★
Range	★★★★★	★★★★★	★ (note4)	★★★
Cost	★	★	★★★★	★★★★★
Ease of data retrieval	★★★★★	★★★★★	★	★★★★

Table I

Note: Grades 1 - 5 Stars represent worst-to-best (5 Stars being best) in each respective category.

Notes:

1. For E5052B the accuracy is good after very long test time.
2. For 5120A-01, the resolution on the floor is insufficient.
3. To achieve accurate data.
4. Limited to 30 MHz

Acknowledgement

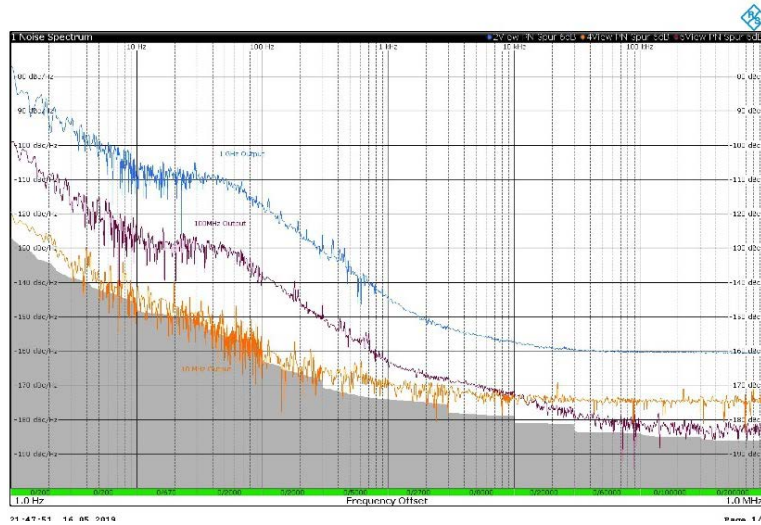
Authors would like to thank Guillaume De Giovanni from Noise XT for support in better understanding DCNTS operation and providing test data, and Dr. Jakub Kucera from Anapico for support and updates.

References

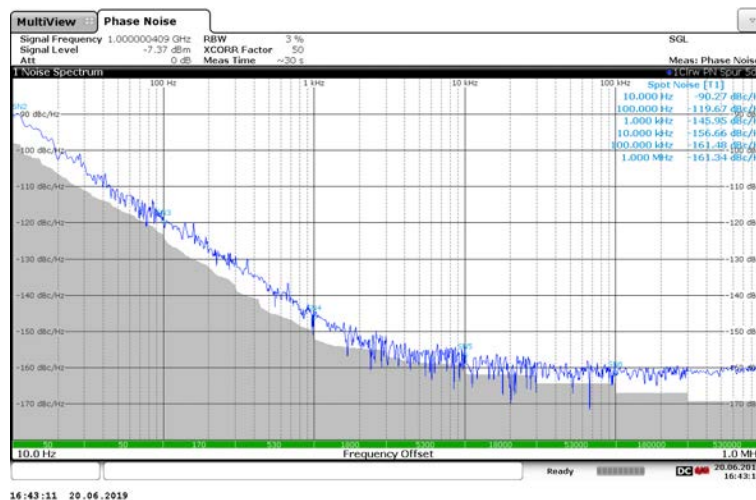
- [1] F.L. Walls et al. Extending the Range and Accuracy of Phase Noise Measurements. Proceedings of the 42nd Annual Symposium on Frequency Control, 1988.
- [2] G. De Giovanni, M. Chomiki. New Phase Measurement Techniques and Ultra Low Noise SAW Oscillator. Proceedings of IEEE International Frequency Control Symposium, 2010, pp. 116 – 118.
- [3] Symmetricom. 5120A Data Sheet.
- [4] Noise XT. DNTCS manual.
- [5] Agilent. E5052B Data Sheet.
- [6] Anapico. APPH6000 Data Sheet.

Addendum

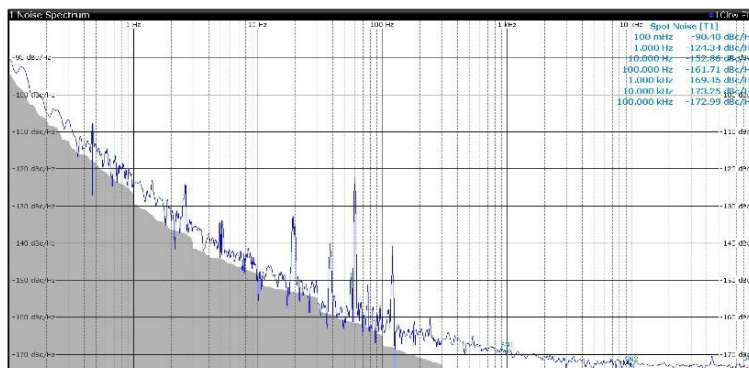
Since the paper was written, a couple more capable instruments come into play for phase noise testing of ULPN crystal oscillators. The most notable is Rohde & Schwarz R&MP;SRFSWP-B61 Low phase noise with cross correlation. The instrument is fast (in most cases), easy to use, covers wide range of input frequencies and offset frequencies. It allows to relatively easy test DFRM and Multi Frequency Reference Module (MFRM) higher frequency outputs phase noise in one shot without concatenation (splicing). Here's an example of the MFRM all outputs obtained without splicing on the same screen.



Another example is 1 GHz ULPN OCXO. The test time was mere 30 seconds and the data is sufficiently accurate.



One area where instrument struggles is 10 MHz ULPN OCXO at 10 Hz offset from the carrier. With specified sensitivity at -132 dBc/Hz at this point and the actual phase noise at -150 dBc/Hz it would require several thousands cross correlations (a few hours) to get close to real value.



Of course, the cost of the instrument is higher than everything else reviewed.

Another instrument worth mentioning is HA7062 Phase Noise analyzer from Holzworth Instruments. It's reasonably fast, easy to use and accurate in most cases. With every new revision though Holzworth makes trade-offs based on market demand. The "C" version is faster, but it cannot reach the floor of -190 dBc/Hz for 100 MHz ULPN OCXO. However, it is not critical for most of their customer base.

One interesting addition to the phase noise testers is coming from Jackson Labs, but it's not released yet and NEL plans to review it once available.

Category	Test Instrument for testing phase noise ULPN OCXO			
	DCNTS	E5052B	5120A-01	APPH6000
Accuracy	★★★★★	★★★★ (note1)	★★★★ (note2)	★★★★
Speed	★★★★★	★ (note3)	★★★★	★★★★★
Ease of use	★★	★★★★	★★★★★	★
Range	★★★★★	★★★★★	★ (note4)	★★★★
Cost	★	★	★★★★	★★★★★
Ease of data retrieval	★★★★★	★★★★★	★	★★★★

Updated Table